

**Supporting Information**

**Perovskite Photodetectors Prepared by Flash  
Evaporation Printing**

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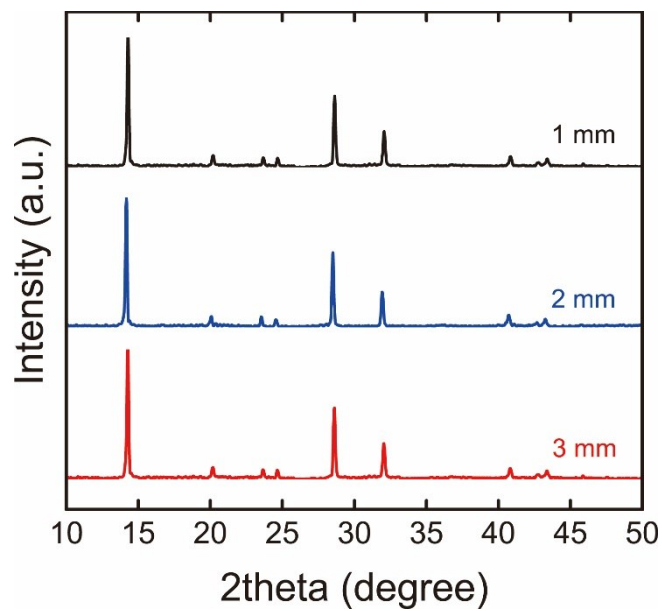
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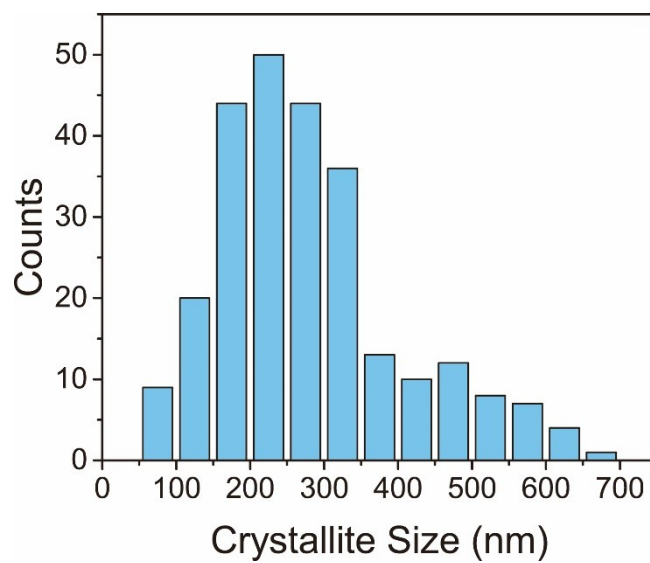
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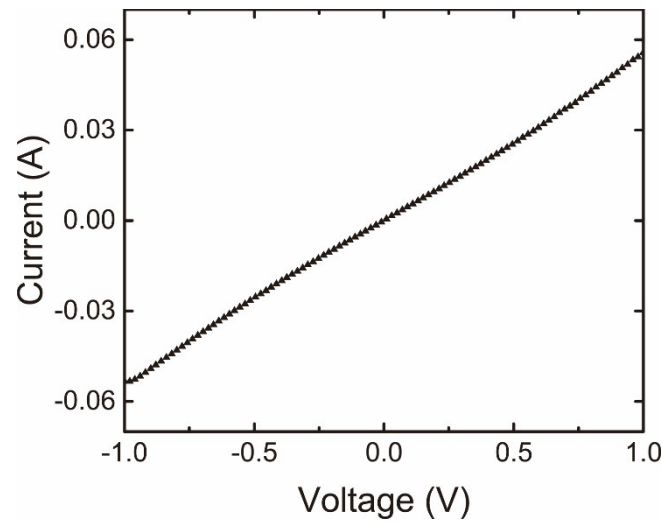
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**Fig. S1** XRD patterns of the perovskite thin films evaporated through different distances between the source and the substrate.



**Fig. S2** Crystallite size distribution of the perovskite thin film in Fig. 2a.



**Fig. S3** *I-V* characteristics of the FTO/MAPbI<sub>3</sub>/Au device for determination of the electrical conductivity.